



TS IEC 62804-1:2015

Photovoltaic (PV) Modules - Test Methods for the detection of potential-induced degradation

Part 1: Crystalline silicon
Confirmation of test results

File Ref.: 10004/2018-40021

Applicant: Changzhou EGing Photovoltaic Technology Co., Ltd.
No. 18 Jinwu Road, 213213 Jintan City, China

Product: Crystalline silicon Photovoltaic (PV)-Modules

Type: A) EG-XXXM60-C
B) EG-XXXP60-C

XXX in the type replaces the power in watt and can be any number between:

200 – 320 for A)
200 – 290 for B)

Manufacturer: Changzhou EGing Photovoltaic Technology Co., Ltd.

Standard: TS IEC 62804-1:2015

Test conditions

Testing time: 192 h

Chamber temperature: 85°C

Relative Humidity: 85 %

Potential to ground: - 1000 V

Pass criteria

Power degradation: < 5%

Dry Insulation: > 40 MΩm²

Wet insulation: > 40 MΩm²



Summary of test results:

Maximum power degradation:	allowed	max. 5 %
	measured	max. 2.43 %

The measured degradation is below the allowed degradation.

Dry insulation resistance:	required	min. 24,5 MΩ
	measured	>500 MΩ

The measured dry insulation resistance is above the limit.

Wet insulation resistance:	required	min. 24,5 MΩ
	measured	>500 MΩ

The measured wet insulation resistance is above the limit.

Visual inspection: No findings

The relevant bill of materials is given in TRPVM-2018-40021-2.

The complete test results are given in Test Report No.: TRPVM-2018-40021-2.

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